

## FQB25N33 330V N-Channel MOSFET

### Features

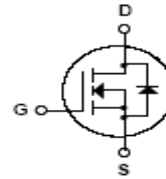
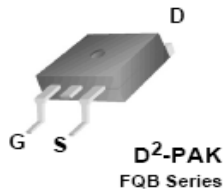
- 25A, 330V,  $R_{DS(on)} = 0.23\Omega @ V_{GS} = 10V$
- Low gate charge (typical 58nC)
- Low Crss (typical 40pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- Qualified to AEC Q101
- RoHS Compliant



### General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimized on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies, active power factor correction, electronic lamp ballast based on half bridge topology.



### Absolute Maximum Ratings

| Symbol         | Parameter                                                                    | FQB25N33    | Units               |
|----------------|------------------------------------------------------------------------------|-------------|---------------------|
| $V_{DSS}$      | Drain-Source Voltage                                                         | 330         | V                   |
| $I_D$          | Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ )                      | 25          | A                   |
|                | - Continuous ( $T_C = 100^\circ\text{C}$ )                                   | 16.0        | A                   |
| $I_{DM}$       | Drain Current - Pulsed (Note 1)                                              | 100         | A                   |
| $V_{GSS}$      | Gate -Source Voltage                                                         | $\pm 30$    | V                   |
| $E_{AS}$       | Single Pulse Avalanche Energy (Note 2)                                       | 370         | mJ                  |
| $I_{AR}$       | Avalanche Current (Note 1)                                                   | 25          | A                   |
| $E_{AR}$       | Repetitive Avalanche Energy (Note 1)                                         | 37          | mJ                  |
| dv/dt          | Peak Diode Recovery dv/dt (Note 3)                                           | 4.5         | V/ns                |
| $P_D$          | Power Dissipation ( $T_A = 25^\circ\text{C}$ ) *                             | 3.1         | W                   |
|                | Power Dissipation ( $T_C = 25^\circ\text{C}$ )                               | 250         | W                   |
|                | - Derate above $25^\circ\text{C}$                                            | 2.0         | W/ $^\circ\text{C}$ |
| $T_J, T_{STG}$ | Operating and Storage Temperature                                            | -55 to +150 | $^\circ\text{C}$    |
| $T_L$          | Maximum lead temperature for soldering purposes, 1/8 from case for 5 seconds | 300         | $^\circ\text{C}$    |

### Thermal Characteristics

| Symbol          | Parameter                                 | FQB25N33 | Units                     |
|-----------------|-------------------------------------------|----------|---------------------------|
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case      | 0.5      | $^\circ\text{C}/\text{W}$ |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient * | 40       | $^\circ\text{C}/\text{W}$ |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient   | 62.5     | $^\circ\text{C}/\text{W}$ |

\* When mounted on the minimum pad size recommended (PCB Mount)

## Package Marking and Ordering Information

| Device Marking | Device   | Package | Reel Size | Tape Width | Quantity |
|----------------|----------|---------|-----------|------------|----------|
| FQB25N33       | FQB25N33 | D2-PAK  | 330mm     | 24mm       | 800      |

## Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|--------|-----------|-----------------|-----|-----|-----|-------|
|--------|-----------|-----------------|-----|-----|-----|-------|

### Off Characteristics

|                                      |                                           |                                                                                               |     |      |         |                     |
|--------------------------------------|-------------------------------------------|-----------------------------------------------------------------------------------------------|-----|------|---------|---------------------|
| $B_{VDSS}$                           | Drain-Source Breakdown Voltage            | $I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$                                                    | 330 | --   | --      | V                   |
| $\frac{\Delta B_{VDSS}}{\Delta T_J}$ | Breakdown Voltage Temperature Coefficient | $I_D = 250\mu\text{A}$ , Referenced to $25^\circ\text{C}$                                     | --  | 0.34 | --      | V/ $^\circ\text{C}$ |
| $I_{DSS}$                            | Zero Gate Voltage Drain Current           | $V_{DS} = 330\text{V}, V_{GS} = 0\text{V}$<br>$V_{DS} = 264\text{V}, T_C = 125^\circ\text{C}$ | --  | --   | 1<br>10 | $\mu\text{A}$       |
| $I_{GSSF}$                           | Gate-Body Leakage Current, Forward        | $V_{GS} = 30\text{V}, V_{DS} = 0\text{V}$                                                     | --  | --   | 100     | nA                  |
| $I_{GSSR}$                           | Gate-Body Leakage Current, Reverse        | $V_{GS} = -30\text{V}, V_{DS} = 0\text{V}$                                                    | --  | --   | -100    | nA                  |

### On Characteristics

|              |                               |                                                      |     |      |      |          |
|--------------|-------------------------------|------------------------------------------------------|-----|------|------|----------|
| $V_{GS(th)}$ | Gate Threshold Voltage        | $V_{DS} = V_{GS}, I_D = 250\mu\text{A}$              | 3.0 | --   | 5.0  | V        |
| $R_{DS(on)}$ | Drain to Source On Resistance | $V_{GS} = 10\text{V}, I_D = 12.5\text{A}$            | --  | 0.18 | 0.23 | $\Omega$ |
| $g_{FS}$     | Forward Transconductance      | $V_{DS} = 50\text{V}, I_D = 12.5\text{A}$ , (Note 4) | --  | 1    | --   | S        |

### Dynamic Characteristics

|           |                              |                                                                    |    |      |      |    |
|-----------|------------------------------|--------------------------------------------------------------------|----|------|------|----|
| $C_{iss}$ | Input Capacitance            | $V_{DS} = 25\text{V}, V_{GS} = 0\text{V}$ ,<br>$f = 1.0\text{MHz}$ | -- | 1510 | 2010 | pF |
| $C_{oss}$ | Output Capacitance           |                                                                    | -- | 290  | 385  | pF |
| $C_{rss}$ | Reverse Transfer Capacitance |                                                                    | -- | 40   | 60   | pF |

### Switching Characteristics

|              |                            |                                                                                      |    |      |     |    |
|--------------|----------------------------|--------------------------------------------------------------------------------------|----|------|-----|----|
| $t_{d(on)}$  | Turn-On Delay Time         | $V_{DD} = 165\text{V}, I_D = 25\text{A}$<br>$R_{GS} = 25\Omega$<br>(Note 4, 5)       | -- | 20   | 35  | ns |
| $t_r$        | Turn-On Rise Time          |                                                                                      | -- | 100  | 160 | ns |
| $t_{d(off)}$ | Turn-Off Delay Time        |                                                                                      | -- | 90   | 145 | ns |
| $t_f$        | Turn-Off Fall Time         |                                                                                      | -- | 70   | 110 | ns |
| $Q_{g(TOT)}$ | Total Gate Charge          | $V_{DS} = 297\text{V}, I_D = 25\text{A}$ ,<br>$V_{GS} = 15\text{V}$ ,<br>(Note 4, 5) | -- | 58   | 75  | nC |
| $Q_{gs}$     | Gate to Source Gate Charge |                                                                                      | -- | 11.2 | --  | nC |
| $Q_{gd}$     | Gate to Drain Charge       |                                                                                      | -- | 21   | --  | nC |

### Drain-Source Diode Characteristics and Maximum Ratings

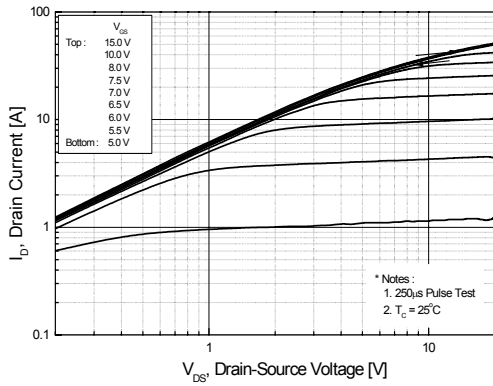
|          |                                                       |                                              |    |     |     |               |
|----------|-------------------------------------------------------|----------------------------------------------|----|-----|-----|---------------|
| $I_S$    | Maximum Continuous Drain-Source Diode Forward Current | --                                           | -- | 25  | A   |               |
| $I_{SM}$ | Maximum Pulsed Drain-Source Diode Forward Current     | --                                           | -- | 100 | A   |               |
| $V_{SD}$ | Drain-Source Diode Forward Voltage                    | $V_{GS} = 0, I_S = 25\text{A}$               | -- | --  | 1.5 | V             |
| $t_{rr}$ | Reverse Recovery Time                                 | $V_{GS} = 0, I_S = 25\text{A}$ ,             | -- | 275 | --  | ns            |
| $Q_{rr}$ | Reverse Recovery Charge                               | $di_F/dt = 100\text{A}/\mu\text{s}$ (Note 4) | -- | 3.6 | --  | $\mu\text{C}$ |

#### Notes:

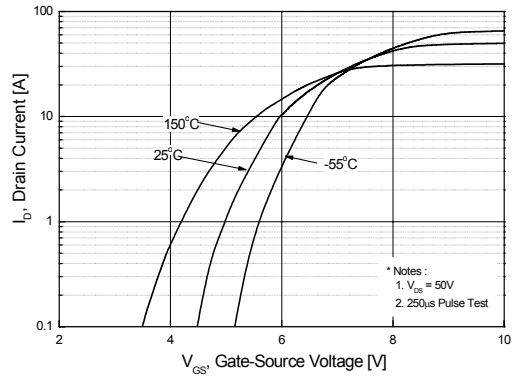
- 1: Repetitive Rating : Pulse width Limited by maximum junction temperature
- 2:  $L = 1.79\text{mH}, I_{AS} = 25\text{A}, V_{DD} = 50\text{V}, R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
- 3:  $I_{SD} \leq 25\text{A}, di/dt \leq 200\text{A}/\mu\text{s}, V_{DD} \leq B_{VDSS}$ , Starting  $T_J = 25^\circ\text{C}$
- 4: Pulse Test : Pulse width  $\leq 300\mu\text{s}$ , Duty cycle  $\leq 2\%$
- 5: Essentially independent of operating temperature

## Typical Performance Characteristics

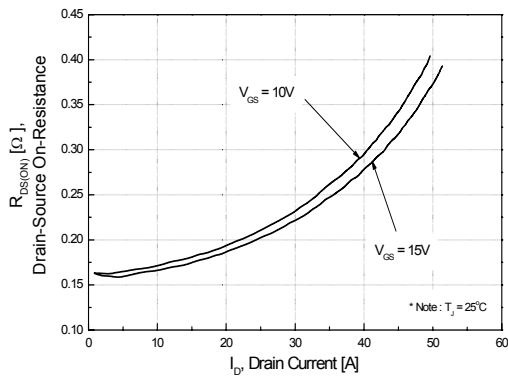
**Figure 1. On-Region Characteristics**



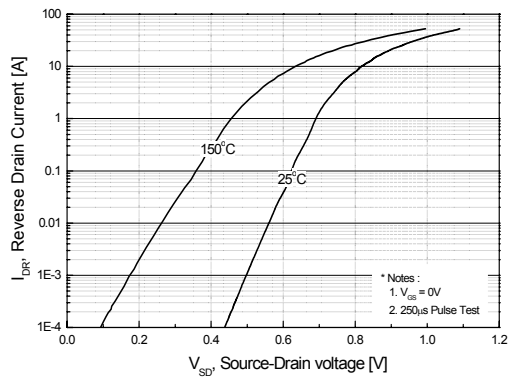
**Figure 2. Transfer Characteristics**



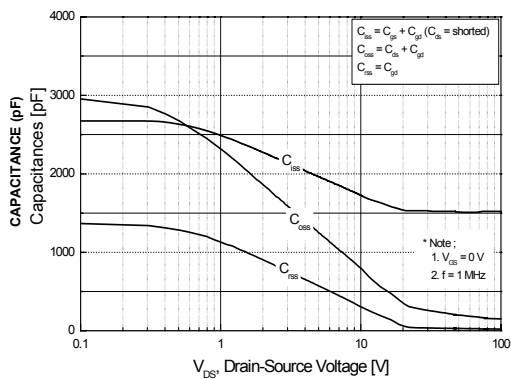
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



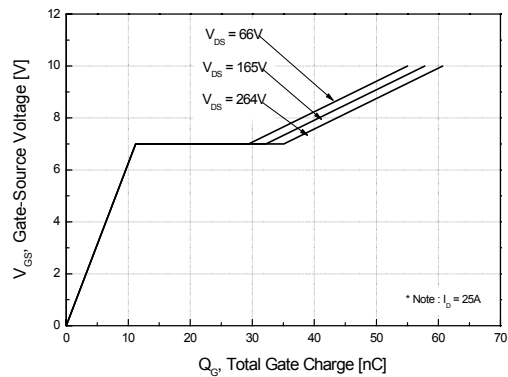
**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**



**Figure 5. Capacitance Characteristics**

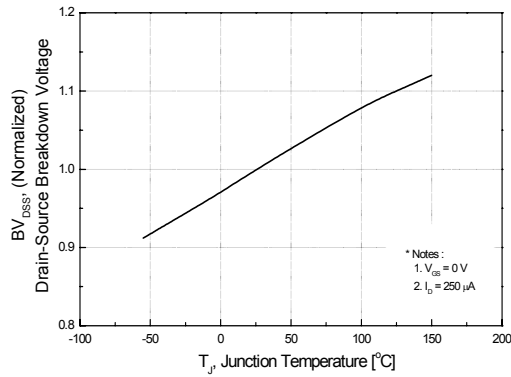


**Figure 6. Gate Charge Characteristics**

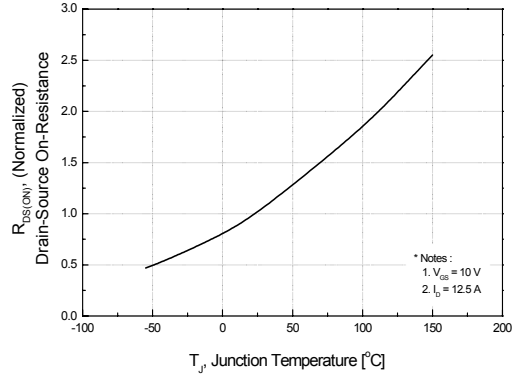


**Typical Performance Characteristics (Continued)**

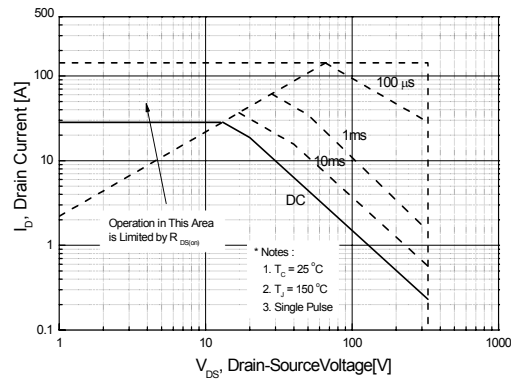
**Figure 7. Breakdown Voltage Variation vs. Temperature**



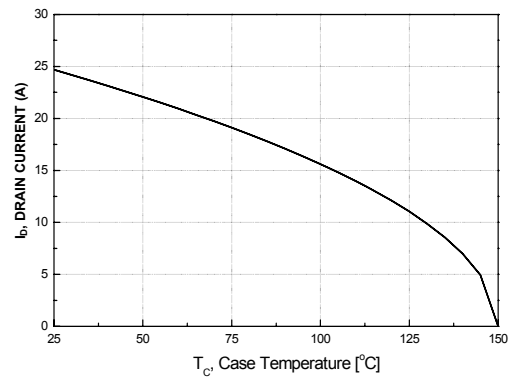
**Figure 8. On-Resistance Variation vs. Temperature**



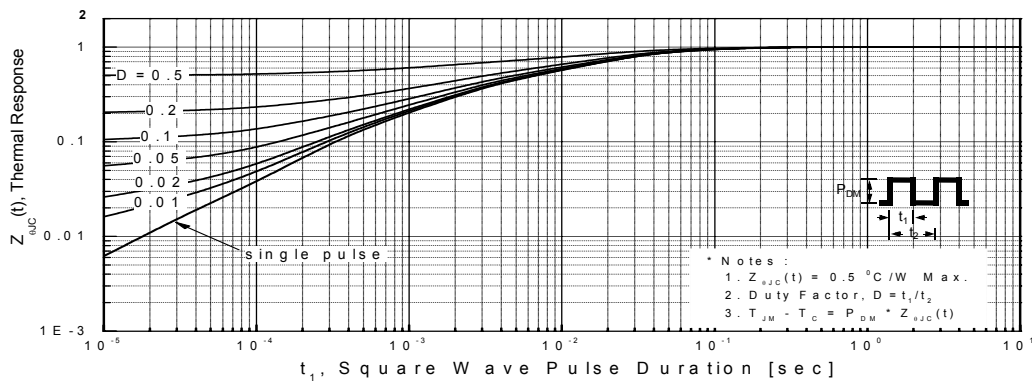
**Figure 9. Maximum Safe Operating Area**



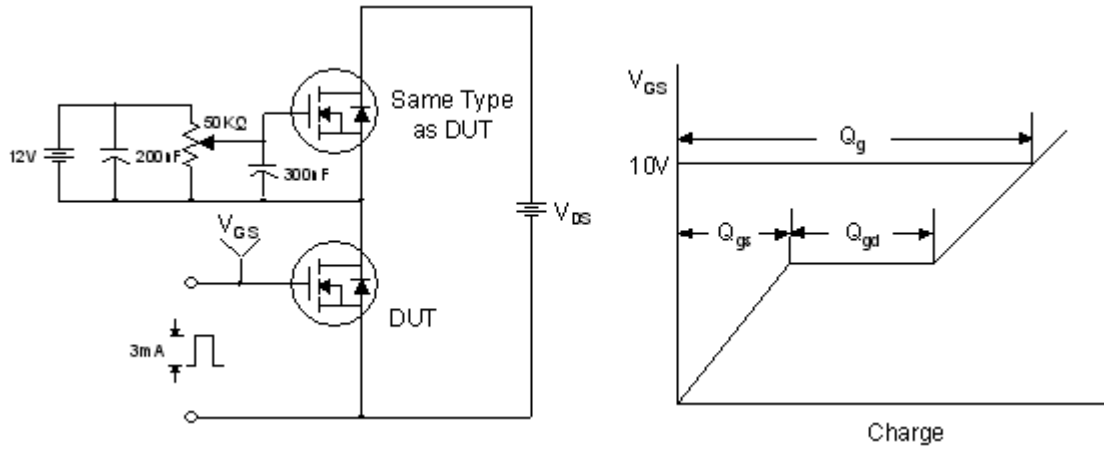
**Figure 10. Maximum Drain Current vs. Case Temperature**



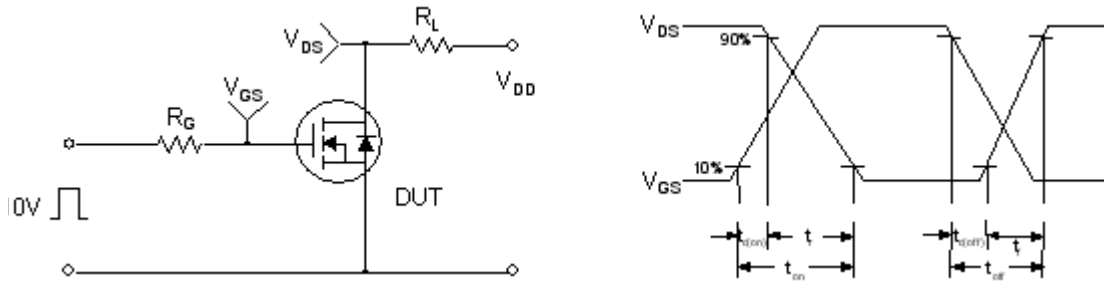
**Figure 11. Transient Thermal Response Curve**



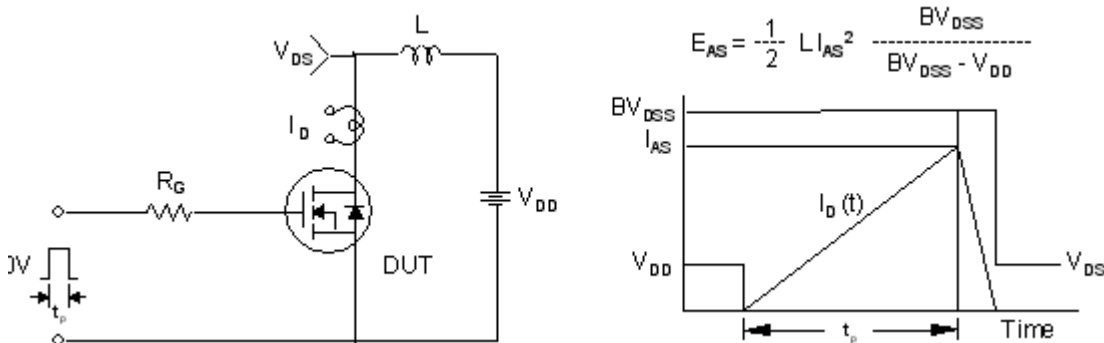
**Gate Charge Test Circuit & Waveform**



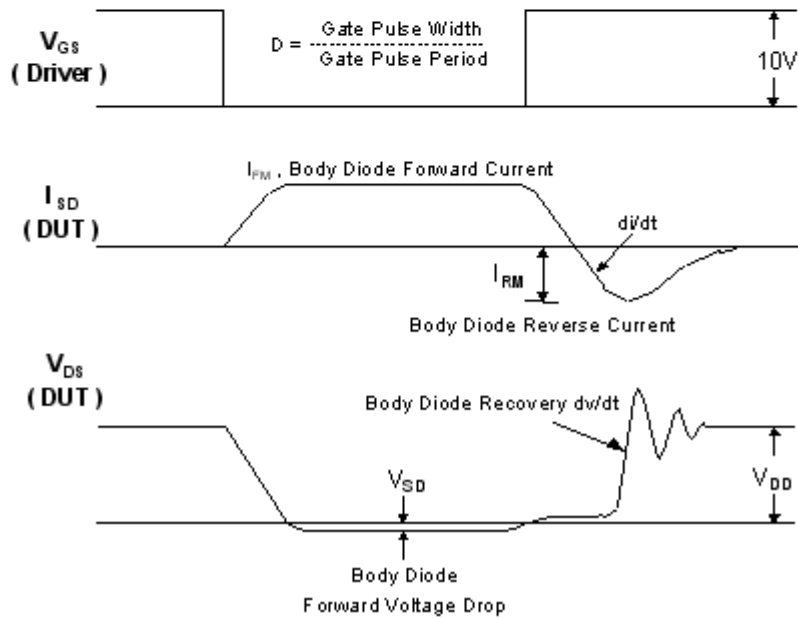
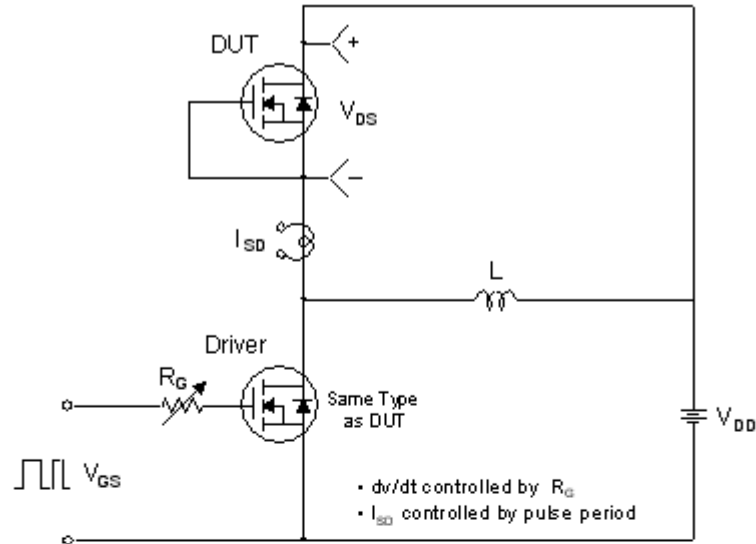
**Resistive Switching Test Circuit & Waveforms**



**Unclamped Inductive Switching Test Circuit & Waveforms**

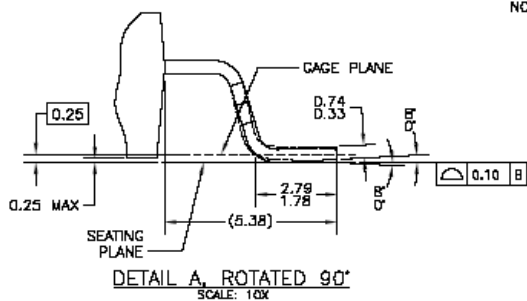
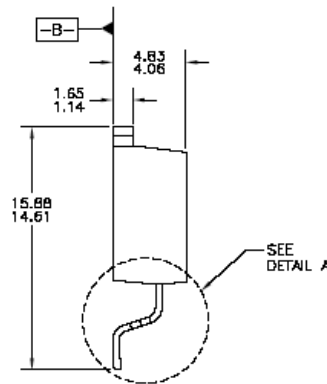
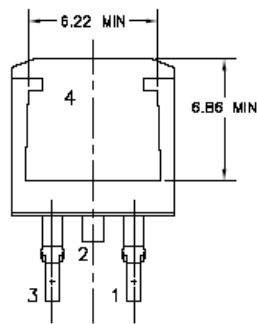
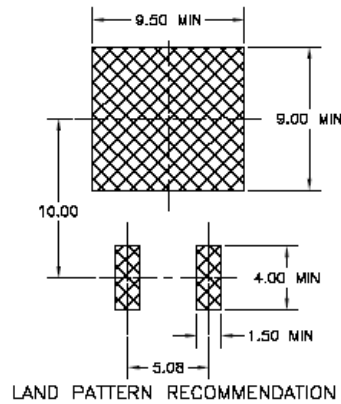
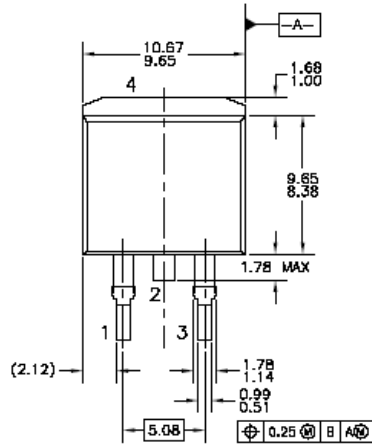


Peak Diode Recovery dv/dt Test Circuit & Waveforms



# Package Dimensions

## D2-PAK



- NOTES: UNLESS OTHERWISE SPECIFIED
- A) ALL DIMENSIONS ARE IN MILLIMETERS.
  - B) REFERENCE JEDEC, TO-263, ISSUE D, VARIATION AB, DATED JULY 2003.
  - C) DIMENSIONING AND TOLERANCING PER ANSI Y14.5M - 1982.
  - D) LOCATION OF THE PIN HOLE MAY VARY (LOWER LEFT CORNER, LOWER CENTER AND CENTER OF THE PACKAGE).
  - E) PRESENCE OF TRIMMED CENTER LEAD IS OPTIONAL.

T02B3AD2REVD

Dimensions in Millimeters

Ultrafast Recovery Power Rectifier

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|                                      |                     |                     |                  |           |
|--------------------------------------|---------------------|---------------------|------------------|-----------|
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| ActiveArray™                         | GlobalOptoisolator™ | OCXPro™             | SMART START™     | UltraFET® |
| Bottomless™                          | GTO™                | OPTOLOGIC®          | SPM™             | VCX™      |
| Build it Now™                        | HiSeC™              | OPTOPLANAR™         | Stealth™         | Wire™     |
| CoolFET™                             | I <sup>2</sup> C™   | PACMAN™             | SuperFET™        |           |
| CROSSVOLT™                           | i-Lo™               | POP™                | SuperSOT™-3      |           |
| DOME™                                | ImpliedDisconnect™  | Power247™           | SuperSOT™-6      |           |
| EcoSPARK™                            | IntelliMAX™         | PowerEdge™          | SuperSOT™-8      |           |
| E <sup>2</sup> CMOS™                 | ISOPLANAR™          | PowerSaver™         | SyncFET™         |           |
| EnSigna™                             | LittleFET™          | PowerTrench®        | TCM™             |           |
| FACT™                                | MICROCOUPLER™       | QFET®               | TinyBoost™       |           |
| FAST®                                | MicroFET™           | QS™                 | TinyBuck™        |           |
| FASTr™                               | MicroPak™           | QT Optoelectronics™ | TinyPWM™         |           |
| FPS™                                 | MICROWIRE™          | Quiet Series™       | TinyPower™       |           |
| FRFET™                               | MSX™                | RapidConfigure™     | TinyLogic®       |           |
|                                      | MSXPro™             | RapidConnect™       | TINYOPTO™        |           |
| Across the board. Around the world.™ |                     | µSerDes™            | TruTranslation™  |           |
| The Power Franchise®                 |                     | ScalarPump™         | UHC™             |           |
| Programmable Active Droop™           |                     |                     |                  |           |

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|--------------------------|------------------------|-----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
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